



UCD4071

CMOS IC

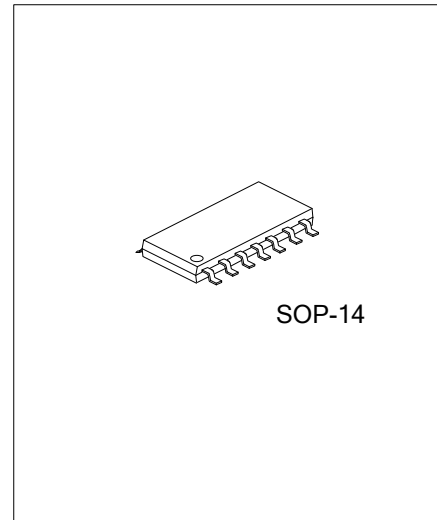
QUAD 2-INPUT OR BUFFERED B SERIES GATE

DESCRIPTION

The **UTC UCD4071** contains four independent 2-input OR gates and they perform the function $Y=A+B$ in positive logic.

FEATURES

- * 5V-10V-15V Parametric Ratings
- * Quad 2-Input OR Gate
- * Symmetrical Output Characteristics
- * Maximum Input Current of 1uA at 15V Over Full Package Temperature
- * Low Power TTL:
Fan Out of 2 Driving 74L or 1 Driving 74LS Compatibility

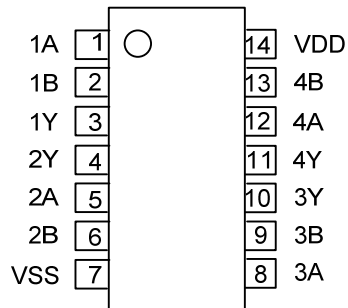


ORDERING INFORMATION

Ordering Number		Package	Packing
Lead Free	Halogen Free		
UCD4071L-S14-R	UCD4071G-S14-R	SOP-14	Tape Reel

<p>UCD4071L-S14-R</p> <p>(1)Packing Type</p> <p>(2)Package Type</p> <p>(3)Lead Free</p>	<p>(1) R: Tape Reel</p> <p>(2) S14: SOP-14</p> <p>(3) G: Halogen Free, L: Lead Free</p>
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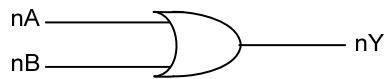
■ PIN CONFIGURATION



■ FUNCTION TABLE (each gate)

INPUT(A)	INPUT(B)	OUTPUT(Y)
H	H	H
H	L	H
L	H	H
L	L	L

■ LOGIC DIAGRAM (positive logic)



■ ABSOLUTE MAXIMUM RATING($T_A=25^{\circ}\text{C}$, unless otherwise specified)

PARAMETER	SYMBOL	RATINGS	UNIT
Supply Voltage	VDD	-0.5 ~ 18	V
Input Voltage	V(nA,nB)	-0.5 ~ VDD +0.5	V
Output Voltage	V(nY)	-0.5 ~ VDD +0.5	V
Storage Temperature	T_{STG}	-65 ~ + 150	$^{\circ}\text{C}$
Lead Temperature(Soldering,10s)	T_L	260	$^{\circ}\text{C}$

Note: Absolute maximum ratings are those values beyond which the device could be permanently damaged.
Absolute maximum ratings are stress ratings only and functional device operation is not implied.

■ RECOMMENDED OPERATING CONDITIONS

PARAMETER	SYMBOL	RATINGS	UNIT
Supply Voltage	VDD	3 ~ 15	V
Operating Temperature	T_{OP}	-40 ~ +125	$^{\circ}\text{C}$

■ ELECTRICAL CHARACTERISTICS($T_A=25^{\circ}\text{C}$, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
High-Level Input Voltage	V_{IH}	VDD= 5V, VO=0.5V	3.5	3		V
		VDD= 10V, VO=1.0V	7.0	6		
		VDD= 15V, VO=1.5V	11.0	9		
Low-Level Input Voltage	V_{IL}	VDD= 5V, VO=4.5V		2	1.5	V
		VDD= 10V, VO=9.0V		4	3.0	
		VDD= 15V, VO=13.5V		6	4.0	
High-Level Output Voltage	V_{OH}	VDD= 5V, $I_{OH}=1\mu\text{A}$	4.95	5		V
		VDD= 10V, $I_{OH}=1\mu\text{A}$	9.95	10		
		VDD= 15V, $I_{OH}=1\mu\text{A}$	14.95	15		
Low-Level Output Voltage	V_{OL}	VDD= 5V, $I_{OL}=1\mu\text{A}$		0	0.05	V
		VDD= 10V, $I_{OL}=1\mu\text{A}$		0	0.05	
		VDD= 15V, $I_{OL}=1\mu\text{A}$		0	0.05	
High-Level Output Current (NOTE)	I_{OH}	VDD= 5V, VO=4.6V	-0.51	-0.88		mA
		VDD= 10V, VO=9.5V	-1.3	-2.25		
		VDD= 15V, VO=13.5V	-3.4	-8.8		
Low-Level Output Current (NOTE)	I_{OL}	VDD= 5V, VO=0.4V	0.51	0.88		mA
		VDD= 10V, VO=0.5V	1.3	2.25		
		VDD= 15V, VO=1.5V	3.4	8.8		
Input Leakage Current	$I_{I(LEAK)}$	VDD= 15V, $V_{IN} = \text{VDD or GND}$			0.1	μA
Quiescent Supply Current	I_Q	VDD= 5V, $V_{IN} = \text{VDD or VSS}$, $I_{OUT} = 0$		0.004	0.25	μA
		VDD= 10V, $V_{IN} = \text{VDD or VSS}$, $I_{OUT} = 0$		0.005	0.5	
		VDD= 15V, $V_{IN} = \text{VDD or VSS}$, $I_{OUT} = 0$		0.006	1.0	

Note: I_{OL} and I_{OH} are tested one output at a time

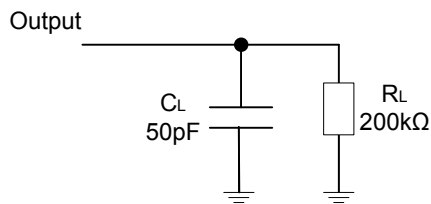
■ SWITCHING CHARACTERISTICS($T_A=25^\circ\text{C}$, Input: $t_R=t_F=20\text{ns}$, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Propagation delay from Input(A or B) to Output(Y)	t_{PLH}	VDD=5V, $C_L=50\text{pF}$, $R_L=200\text{k}\Omega$		90	250	ns
		VDD=10V, $C_L=50\text{pF}$, $R_L=200\text{k}\Omega$		40	100	
		VDD=15V, $C_L=50\text{pF}$, $R_L=200\text{k}\Omega$		30	70	
	t_{PHL}	VDD=5V, $C_L=50\text{pF}$, $R_L=200\text{k}\Omega$		100	250	
		VDD=10V, $C_L=50\text{pF}$, $R_L=200\text{k}\Omega$		40	100	
		VDD=15V, $C_L=50\text{pF}$, $R_L=200\text{k}\Omega$		30	70	
Transition Time	t_{TLH}	VDD=5V, $C_L=50\text{pF}$, $R_L=200\text{k}\Omega$		90	200	ns
		VDD=10V, $C_L=50\text{pF}$, $R_L=200\text{k}\Omega$		50	100	
	t_{THL}	VDD=15V, $C_L=50\text{pF}$, $R_L=200\text{k}\Omega$		40	80	

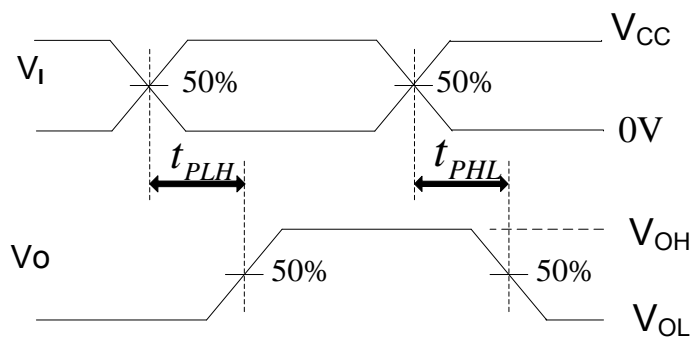
■ OPERATING CHARACTERISTICS($T_A=25^\circ\text{C}$, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Average Input Capacitance	C_{in}	Any Input		5	7.5	μF
Power Dissipation Capacitance	C_{pd}	Any Gate		18		

■ TEST CIRCUIT AND WAVEFORMS



Definitions for test circuit



Propagation Delay Times

Note: CL includes probe and jig capacitance.

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